

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/764,787	SCHWARTZ ET AL.
	Examiner Tan Dean D. Nguyen	Art Unit 3629

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
I US Patent PG Pub	3/06 2011	↓
II FOREIGN 1. EPO 2- JPO 3. Derwent	3/06	↓
4. (BM-TDD)	↓	↓

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner